

Notice of References Cited	Application/Control No. 10/767,768	Applicant(s)/Patent Under Reexamination OGAWA, HIDEHIKO	
	Examiner Thomas D. Lee	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,798,845	08-1998	Baek et al.	358/434
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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